

Conducted Disturbances Test System

IEC / EN 61000-4-6

MIL 461 CS 114, ISO 11452-4, Namur

- The compact device consists of a RF signal generator, a RF-power amplifier, a 3-channel RF voltmeter and a directional coupler
- Frequency range (signal generator)4 kHz-1200 MHz
- The RF power amplifier is available in three different models.



Turn Key Solution for Conducted Immunity Tests

Overview

New test generator for all interference immunity standards against conducted Interference induced by high frequency fields including BCI tests (ISO 11452-4). One of the very few combined IEC 61000 4-6 test systems that include the RF signal generator, a RF power amplifier, a 3-channel RF voltmeter and a directional coupler for a competitive price. The CDG 7000 generates interferences as defined in IEC EN 61000-4-6 immunity to conducted disturbances induced by radio frequency fields.

The standard describes a test setup in which these high frequency interferences can be influenced on a EUT without a complicated structure with antennas, field instrumentation and shielded rooms. By using coupling networks and coupling clamp's sine waves are induced directly into power and signal lines. We offer an extensive range of accessories for this purpose. The test object retains its original place in the device structure, so that the system can be tested in its overall function.

Key Facts

- The included application software (HELIA 7-Basic) enables extensive reporting functions and EUT monitoring (HELIA 7 BCI requires for BCI testing)
- Simple expansion with external amplifier via 2nd generator output
- SCPI command set enables easy integration into own software systems
- Interfaces: USB, LAN, GPIB (option)
- Temperature measuring input, e.g. for monitoring and displaying the BCI clamp temperature
- Input for external pulse modulation
- Configurable, digital 8-channel user port
- Warranty 3 years





Conducted Disturbances Test System

Models	
CDG 7000-25	Conducted RF generator, acc. IEC 61000-4-6 100 kHz - 250 MHz, amplifier 25 W Maximum test level: 10 V (15 V) with 80 % AM (without 6 dB) Built-in directional coupler, with software HELIA 7 - Basic USB, LAN
CDG 7000-75	Conducted RF generator, acc. IEC 61000-4-6 100 kHz - 400 MHz, amplifier 75 W Maximum test level: 30 V (40 V) with 80% AM (without 6 dB) Built-in directional coupler with software HELIA 7 - Basic USB, LAN
CDG 7000-75-10	Conducted RF generator, acc. IEC 61000-4-6 10kHz - 250 MHz, amplifier 75 W Maximum test level: 30 V (40 V) with 80% AM (without 6 dB) Built-in directional coupler with software HELIA 7 - Basic USB, LAN

Technical data I

25 W .00 kHz-250 MHz 25 W	75 W 100 kHz-400 MHz	75 W / 10k 10 kHz-250 MHz
	100 kHz-400 MHz	10 kHz-250 MHz
25 W		
25 W		
	75 W	75 W
20 W	50 W	50 W
46 dB nominal	51 dB nominal	51 dB nominal
1.5 dB maximum	± 1.5 dB maximum	± 1.5 dB maximum
1 mW / 0 dBm	1 mW / 0 dBm	1 mW / 0 dBm
50 Ω	50 Ω	50 Ω
1.5 : 1 max.	1.5 : 1 max.	1.5 : 1 max.
:-20 dBc @ 20 W	< -20 dBc @ 50 W	< -20 dBc @ 50 W
tup E dD	typ. 7 dB	typ. 7 dB
typ. 5 dB	1, p. , ab	5, p. 7 GB
	1.5 dB maximum 1 mW / 0 dBm 50 Ω 1.5 : 1 max.	1.5 dB maximum \pm 1.5 dB maximum 1 mW / 0 dBm 1 mW / 0 dBm 50 Ω 50 Ω 1.5 : 1 max. 1.5 : 1 max. -20 dBc @ 20 W < -20 dBc @ 50 W



Conducted Disturbances Test System

2 x SMA	
9 kHz - 1.2 GHz (usable from 4 kHz)	
1 Hz	
0 to - 63 dBm	
0.1 dB	
< 30 dBc	
< 45 dBc	
0 - 100 %, resolution 1 %	
0 – 100 % , max. Amplitude 1 V = 100 %, BNC jack	
5 - 95 %,	
resolution 1 %	
DC1 MHz, 3,3/5 V CMOS/TTL, BNC jack	

LF Generator (modulation)			
Connector	BNC jack			
Frequency range	1 Hz - 100 kHz			
Frequency resolution	0.1 Hz			
Signal	Sine wave / square wave / triangular			
Amplitude	01 V			
RF Voltmeter (test level)				
Connector	BNC jack			
Frequency range	9 kHz - 1.2 GHz (usable from 4 kHz)			
Measuring range	-40 to +30 dBm			
RF Voltmeter 2+3 (forward / reverse power)				
Connector	2 x SMA			
Frequency range	9 kHz - 1.2 GHz (usable from 4 kHz)			
Measuring range	-40 to +33 dBm + directional coupler			

(typ. 40 dB)

Technical data II

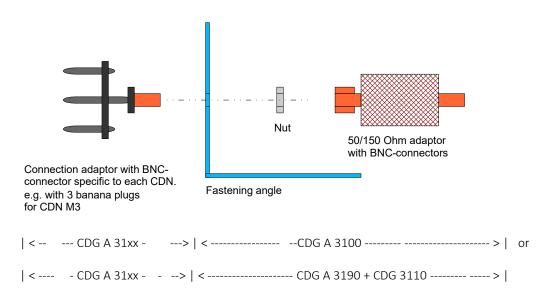
Module				
EUT-MONITOR INPUT				
Input voltage	0 to 10 V DC			
Resolution	2.5 mV			
Input impedance	100 kΩ			
EUT-FAILED INPUT				
Input signal	3,3/5 V CMOS/TTL level			
Detection mode	status or edge controlled			
Temperature	10 - 100 °C (1039 to			
measurement	1385 Ω) resolution			
	< 1 °C (PT 1000)			
SCPI Interfaces				
USB 2.0	USB-B			
LAN, 100 Mbit	RJ45			
GPIB (optional)	Centronics			

Module		
DIGITAL I/OS		
Out	4 Bit Digital out,	
	5 V CMOS/TTL	
In	4 Bit Digital in,	
	5 V CMOS/TTL	
INTERLOCK		
Closes at	R < 1 kΩ	
General data		
Temperature range	0 - 40 °C	
Housing	19" desktop case	
	(84 TE; 3 HE)	
Weight	approx. 11 kg	
Width / height / depth	app. 450 / 135 / 504 mm	
AC Input	100 - 240 VAC; 50/60 Hz	



Conducted Disturbances Test System

Accessories for calibration set I



To calibrate a CDN the following items are required*:

2 x CDG A 31xx (appropriate connection CDN Adapter for AE-side and EUT-side required) 2 x CDG A 3100 (mounting plate + $50/150 \Omega$ passage + 50Ω termination for AE-side)

For the first CDN following is required*:

2 x CDG A 31xx +

2 x CDG A 3100 or 2x (CDG A 3190 + CDG 3110)

For each additional CDN, only 2 corresponding connection adapters need to be ordered*:

2 x CDG A 31xx, optional for each connection adapter also one mounting plate CDG A 3190

Coupling Networks (special CDNs upon request) CDN M1 CDN M4-32/63/100-HV CDN RJ45S ■ CDN L1-16 CDN M5-16/32 CDN USB 3.0 CDN M2-16/32 CDN M5-32/63/100-HV ■ CDN USB-C / USB-P CDN M2-32/63/100-HV CDN CAN-BUS CDN HDMI ■ CDN M2+3-16/32 CDN AF2/ AF3/ AF4 / AF5/ AF8/ AF12 CDN Firewire CDN M3-16/32 CDN T2/T4/T8 ■ CDN D 100 CDN M3-32/63/100-HV ■ CDN RJ11/RJ45 CDN M4-16/32 CDN S1/S2/S3/S4/S8/S9/S15/S25

^{*}Dependent of the signal, termination can be omitted on the AE side. Let us advise you on the details.



Conducted Disturbances Test System

CDN Facts				
CDN EMCL-20		CDN EMCL-35		
 EM-Coupling clamp for cables up to Ø 20 mm Included calibration set and factory calibration Option: With matching network CDN-EMCLNW_10 starting from 10 kHz 		 ■ EM-Coupling clamp for cables up to Ø 35 mm ■ Included calibration set and factory calibration 		
CDN ABCL-20 (Abso	rbing clamp)	CDN ABCL-35 (Abs	orbing clamp)	
■ For cables up to Ø	<u> </u>	■ For cables up to Ø 35 mm		
•	coupling at immunity testing	•	ecoupling at immunity testing	
according to IEC /		according to IEC		
CDN BCI-P1		CDN BCI-P1_MT1		
 Injection probe fo 	or Bulk Current Injection (BCI)	 Additional transformator for CDN BCI-P1 		
 Frequency range: 	1 - 400 MHz	■ Frequency range 1 - 400 MHz		
■ For cables up to Ø	5 40 mm	■ For cables up to Ø 40 mm		
 Included calibration set 		 Included calibration set 		
CDG CMP-45		CDG CMP-46		
 Current monitorir 	ng probe 10 kHz - 400 MHz,	 Current monitoring probe 10 kHz - 400 MHz, 		
foldable			not foldable	
■ For cables up to Ø 45 mm		■ For cables up to Ø 46 mm		
Option: Calibration set CDG A CMP-45		Option: Calibration set CDG A CMP-46		
CDN Calibration set				
Mounting angle: (CDG A 3100 (Mounting angle,			
	er, 50 Ω Termination)			
■ Calibration adapte	er: CDG A 31xx			
Attenuators		Termination		
■ CDG 7050-20W	6 dB Attenuator, 20 W	■ CDG A 50	BNC Termination, 50 Ω , 1 W	
CDG 7006-20W	6 dB Attenuator, 20 W	CDG A 50-10W	BNC Termination, 50 Ω , 10 W	
CDG 7006-100W	6 dB Attenuator, 100 W	CDG A 50-50W	BNC Termination, 50 Ω , 50 W	
CDG 7020-20W	20 dB Attenuator, 20 W			

All information regarding appearance and technical data correspond to the current state of development at the time of release of this data sheet. We reserve the right to make technical changes.

222106